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|-----------------------------------|--|-------------------------|--|-------------|
| Notice of References Cited | | Application/Control No. | Applicant(s)/Patent Under Reexamination NAKAGAWA ET AL. | |
| | | Examiner | Art Unit | Page 1 of 1 |
| Louis K. Huynh | | 3721 | | |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|---------------------|----------------|
| | A | US-3,668,815 | 06-1972 | Henry et al. | 53/551 |
| | B | US-4,391,081 | 07-1983 | Kovacs, Lloyd | 53/552 |
| | C | US-5,279,098 | 01-1994 | Fukuda, Masao | 53/551 |
| | D | US-5,836,136 | 11-1998 | Highberger, Gary G. | 53/55 |
| | E | US- | | | |
| | F | US- | | | |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| | | |
|---|---|---|
| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
| | U | |
| | V | |
| | W | |
| | X | |

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